

N-Channel Enhancement Mode Power MOSFET

Description

The HM4444 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

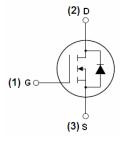
- V_{DS} =80V, I_{D} =12.5A $R_{DS(ON)} < 16mΩ @ V_{GS}$ =10V (Typ:13mΩ)
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

Application

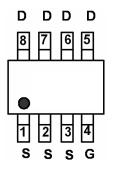
- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

100% UIS TESTED!

100% ΔVds TESTED!



Schematic diagram



'Marking and pin Assignment



. SOP-8 top view

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM4444	HM4444	SOP-8	-		

Absolute Maximum Ratings (T_C=25 ℃unless otherwise noted)

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	80	V	
Gate-Source Voltage	V _{GS}	±20	V	
Drain Current-Continuous	I _D	12.5	Α	
Drain Current-Continuous(T _C =100℃)	I _D (100℃)	8.75	А	
Pulsed Drain Current	I _{DM}	37.5	Α	
Maximum Power Dissipation	P _D	3	W	
Derating factor		0.73	W/℃	
Single pulse avalanche energy (Note 5)	E _{AS}	450	mJ	
Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 175	$^{\circ}$	

Thermal Characteristic

Thermal Resistance, Junction-to-Case (Note 2)	$R_{ heta JC}$	1.36	°C/W

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Electrical Characteristics (T_C=25 °C unless otherwise noted)

Parameter	Symbol	Symbol Condition		Тур	Max	Unit
Off Characteristics	<u>.</u>					
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA 80		-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =80V,V _{GS} =0V	-	-	1	μΑ
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)	•					•
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS},I_{D}=250\mu A$	1.2	1.7	2.5	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =20A	-	13	16	mΩ
Forward Transconductance	g Fs	V _{DS} =10V,I _D =20A	28	-	-	S
Dynamic Characteristics (Note4)			•			
Input Capacitance	C _{lss}	V 05VV 0V	-	2350	-	PF
Output Capacitance	C _{oss}	V _{DS} =25V,V _{GS} =0V,	-	337	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.0MHz	-	165	-	PF
Switching Characteristics (Note 4)	•					•
Turn-on Delay Time	t _{d(on)}		-	12	-	nS
Turn-on Rise Time	t _r	V_{DD} =40 V , I_D =2 A , R_L =2 Ω	-	9	-	nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =10 V , R_{G} =3 Ω	-	20	-	nS
Turn-Off Fall Time	t _f		-	18	-	nS
Total Gate Charge	Q_g	\/ 40\/ L 00A	-	55	-	nC
Gate-Source Charge	Q _{gs}	V _{DS} =40V,I _D =20A,	-	13	-	nC
Gate-Drain Charge	Q_{gd}	V _{GS} =10V	-	16	-	nC
Drain-Source Diode Characteristics			•			
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =20A	-	-	1.2	V
Diode Forward Current (Note 2)	Is		-	-	12.5	Α
Reverse Recovery Time	t _{rr}	TJ = 25°C, IF =20A	-	21		nS
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	65		nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

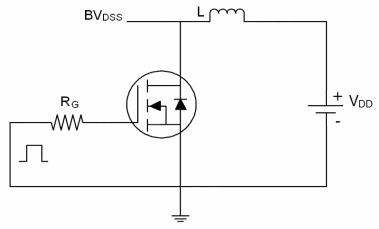
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.
- 4. Guaranteed by design, not subject to production

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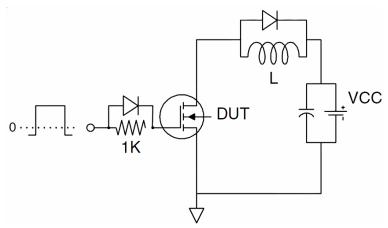


Test Circuit

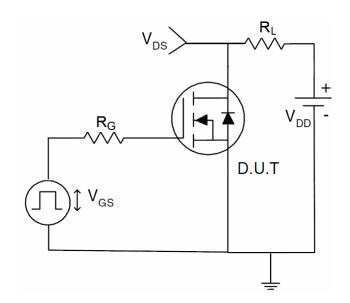
1) E_{AS} test Circuits



2) Gate charge test Circuit



3) Switch Time Test Circuit



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Typical Electrical and Thermal Characteristics (Curves)

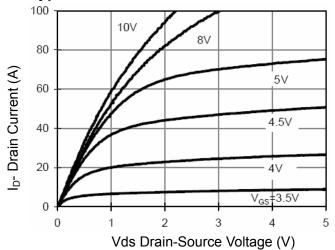


Figure 1 Output Characteristics

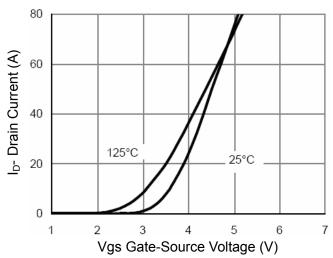


Figure 2 Transfer Characteristics

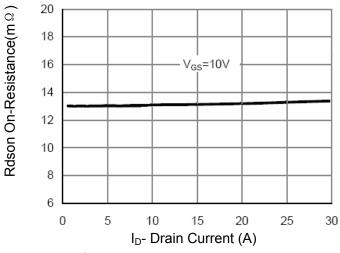


Figure 3 Rdson- Drain Current

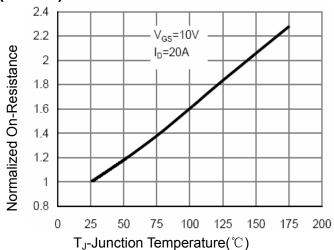


Figure 4 Rdson-Junction Temperature

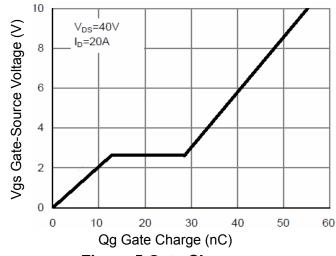


Figure 5 Gate Charge

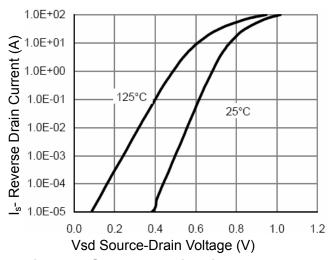


Figure 6 Source- Drain Diode Forward

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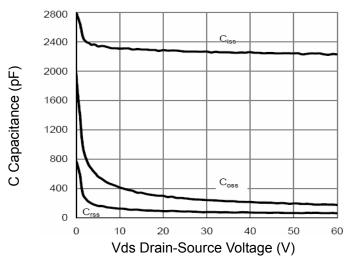


Figure 7 Capacitance vs Vds

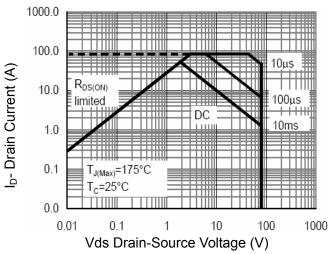


Figure 8 Safe Operation Area

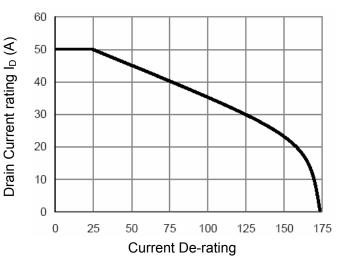


Figure 9 Drain Current vs Junction Temperature

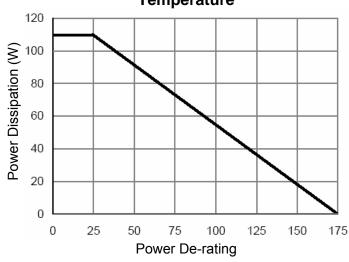


Figure 10 Power vs Junction Temperature

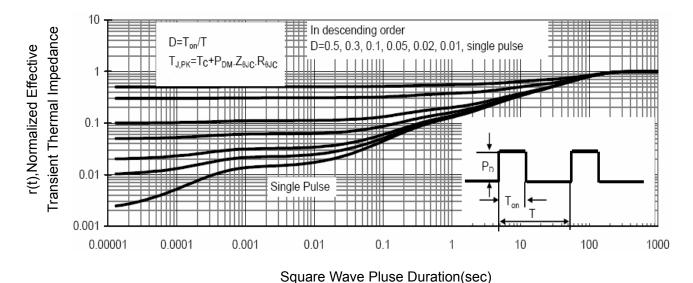
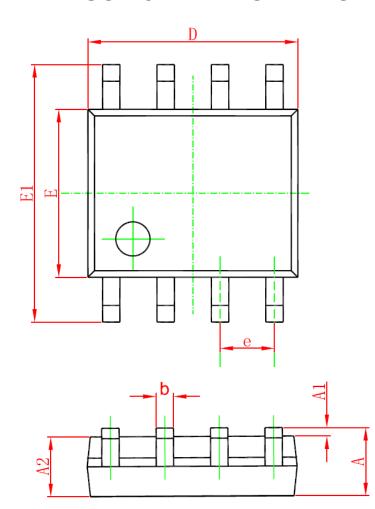


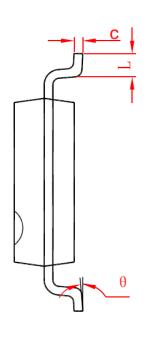
Figure 11 Normalized Maximum Transient Thermal Impedance

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SOP-8 PACKAGE IN FORMATION





Symbol	Dimensions Ir	n Millimeters	Dimensions In Inches		
	Min	Max	Min	Max	
A	1. 350	1. 750	0. 053	0. 069	
A1	0. 100	0. 250	0.004	0. 010	
A2	1. 350	1. 550	0.053	0. 061	
b	0. 330	0. 510	0. 013	0. 020	
С	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
Е	3. 800	4. 000	0. 150	0. 157	
E1	5. 800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
L	0. 400	1. 270	0. 016	0. 050	
θ	0°	8°	0°	8°	

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